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Application/Control No.	Applicant(s)/Patent under Reexamination	
10/785,239	YANG ET AL.	
Examiner	Art Unit	
Miko Oi	2871	

SEARCHED			
Class	Subclass	Date	Examiner
349	38-39; 155,157; 114	3/10/2006	ZQQ

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
East search; US-PGPUB;USPAT;USOCR; EPO;JPO;DERWENT;IBM_TDB; update search; (see search history printout)	3/10/2006	ZQQ